## FEATURES

－Repetitive Avalanche Rated
－Fast switching
－Stable off－state characteristics
－High thermal cycling performance
－Isolated package
－Fast reverse recovery diode

## GENERAL DESCRIPTION

N－channel，enhancement mode field－effect power transistor， incorporating a Fast Recovery Epitaxial Diode（FRED）．This gives improved switching performance in half bridge and full bridge converters making this device particularly suitable for inverters， lighting ballasts and motor control circuits．

The PHX6ND50E is supplied in the SOT186A full pack，isolated package．

SYMBOL


PINNING

| PIN | DESCRIPTION |
| :---: | :--- |
| 1 | gate |
| 2 | drain |
| 3 | source |
| case | isolated |
|  |  |

## QUICK REFERENCE DATA

$$
\begin{gathered}
\mathrm{V}_{\mathrm{DSS}}=500 \mathrm{~V} \\
\mathrm{I}_{\mathrm{D}}=3.1 \mathrm{~A} \\
\mathrm{R}_{\mathrm{DS}(\mathrm{~N})} \leq 1.5 \Omega \\
\mathrm{t}_{\mathrm{r}}=180 \mathrm{~ns}
\end{gathered}
$$

## SOT186A



## LIMITING VALUES

Limiting values in accordance with the Absolute Maximum System（IEC 134）

| SYMBOL | PARAMETER | CONDITIONS | MIN． | MAX． | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: |
| $V_{\text {DSS }}$ | Drain－source voltage | $\mathrm{T}_{\mathrm{j}}=25^{\circ} \mathrm{C}$ to $150^{\circ} \mathrm{C}$ |  | 500 | V |
| $V_{\text {DGR }}$ | Drain－gate voltage | $\mathrm{T}_{\mathrm{j}}=25^{\circ} \mathrm{C}$ to $150^{\circ} \mathrm{C} ; \mathrm{R}_{\mathrm{GS}}=20 \mathrm{k} \Omega$ | － | 500 | V |
| $V_{\text {GS }}$ | Gate－source voltage |  | － | $\pm 30$ | V |
| $\mathrm{I}_{\mathrm{D}}$ | Continuous drain current |  | － | 3.1 | A |
|  | Pulsed drain current ${ }^{1}$ | $\begin{aligned} & \mathrm{T}_{\mathrm{hs}}=100^{\circ} \mathrm{C} ; \mathrm{V}_{\mathrm{GS}}=10 \mathrm{~V} \\ & \mathrm{~T}_{\mathrm{hs}}=25^{\circ} \mathrm{C} \end{aligned}$ | － | 2 | A |
| ${ }_{\text {PM }}$ | Total dissipation | $\mathrm{T}_{\text {hs }}=25^{\circ} \mathrm{C}$ | － | 35 | W |
| $\mathrm{T}_{\mathrm{j}}, \mathrm{T}_{\text {stg }}$ | Operating junction and storage temperature range |  | － 55 | 150 | ${ }^{\circ} \mathrm{C}$ |

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FREDFET, Avalanche energy rated

## AVALANCHE ENERGY LIMITING VALUES

Limiting values in accordance with the Absolute Maximum System (IEC 134)

| SYMBOL | PARAMETER | CONDITIONS | MIN. | MAX. | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{E}_{\text {AS }}$ | Non-repetitive avalanche energy | Unclamped inductive load, $\mathrm{I}_{\mathrm{AS}}=4 \mathrm{~A}$; $\mathrm{t}_{\mathrm{p}}=0.17 \mathrm{~ms} ; \mathrm{T}_{\mathrm{j}}$ prior to avalanche $=25^{\circ} \mathrm{C}$; $\mathrm{V}_{\mathrm{DD}} \leq 50 \mathrm{~V} ; \mathrm{R}_{\mathrm{GS}}=50 \Omega ; \mathrm{V}_{\mathrm{GS}}=10 \mathrm{~V}$; refer to fig:17 <br> $\mathrm{I}_{\mathrm{AR}}=5.9 \mathrm{~A} ; \mathrm{t}_{\mathrm{p}}=1 \mu \mathrm{~s} ; \mathrm{T}_{\mathrm{j}}$ prior to avalanche $=25^{\circ} \mathrm{C} ; \mathrm{R}_{\mathrm{GS}}=50 \Omega ; \mathrm{V}_{\mathrm{GS}}=10 \mathrm{~V}$; refer to fig:18 | - | 280 | mJ |
| $\mathrm{E}_{\text {AR }}$ | Repetitive avalanche energy ${ }^{1}$ |  | - | 10 | mJ |
| $\mathrm{I}_{\text {AS }}, \mathrm{I}_{\text {AR }}$ | Repetitive and non-repetitive avalanche current |  | - | 5.9 | A |

## ISOLATION LIMITING VALUE \& CHARACTERISTIC

$\mathrm{T}_{\text {hs }}=25^{\circ} \mathrm{C}$ unless otherwise specified

| SYMBOL | PARAMETER | CONDITIONS | MIN. | TYP. | MAX. | UNIT |
| :--- | :--- | :--- | :---: | :---: | :---: | :---: |
| V isol | R.M.S. isolation voltage from all <br> three terminals to external <br> heatsink | $\mathrm{f}=50-60 \mathrm{~Hz}$; sinusoidal <br> waveform; <br> R.H. $\leq 65 \% ;$ clean and dustfree | - |  | 2500 | V |
| C $_{\text {isol }}$ | Capacitance from T2 to external <br> heatsink | $\mathrm{f}=1 \mathrm{MHz}$ | - | 10 | - | pF |

## THERMAL RESISTANCES

| SYMBOL | PARAMETER | CONDITIONS | MIN. | TYP. | MAX. | UNIT |
| :--- | :--- | :--- | :---: | :---: | :---: | :---: |
| $R_{\text {th } j \text {-hs }}$ | Thermal resistance junction <br> to heatsink | with heatsink compound | - | - | 3.6 | $\mathrm{~K} / \mathrm{W}$ |
| $\mathrm{R}_{\mathrm{th} j-\mathrm{a}}$ | Thermal resistance junction <br> to ambient |  | - | 55 | - | $\mathrm{K} / \mathrm{W}$ |

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## ELECTRICAL CHARACTERISTICS

$\mathrm{T}_{\mathrm{j}}=25^{\circ} \mathrm{C}$ unless otherwise specified

| SYMBOL | PARAMETER | CONDITIONS | MIN. | TYP. | MAX. | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\text {(BR) } \mathrm{DSS}}$ | Drain-source breakdown voltage | $\mathrm{V}_{\mathrm{GS}}=0 \mathrm{~V} ; \mathrm{I}_{\mathrm{D}}=0.25 \mathrm{~mA}$ | 500 | - | - | V |
| $\begin{aligned} & \Delta \mathrm{V}_{\text {(BR)DSs }} / \\ & \Delta \mathrm{T}_{\mathrm{j}} \end{aligned}$ | Drain-source breakdown voltage temperature coefficient | $\mathrm{V}_{\mathrm{DS}}=\mathrm{V}_{\mathrm{GS}} ; \mathrm{I}_{\mathrm{D}}=0.25 \mathrm{~mA}$ | - | 0.1 | - | \%/K |
| $\mathrm{R}_{\text {DS(ON) }}$ | Drain-source on resistance | $V_{G S}=10 \mathrm{~V} ; \mathrm{I}_{\mathrm{D}}=3 \mathrm{~A}$ | - | 1.2 | 1.5 | $\Omega$ |
| $\mathrm{V}_{\mathrm{GS}(\mathrm{TO})}$ | Gate threshold voltage | $V_{\text {DS }}=V_{G S} ; \mathrm{I}_{\mathrm{D}}=0.25 \mathrm{~mA}$ | 2.0 | 3.0 | 4.0 | V |
| $\mathrm{g}_{\mathrm{fs}}$ | Forward transconductance | $\mathrm{V}_{\text {DS }}=30 \mathrm{~V} ; \mathrm{l}_{\mathrm{D}}=3 \mathrm{~A}$ | 2 | 3.6 |  | S |
| $\mathrm{l}_{\text {dss }}$ | Drain-source leakage current | $\mathrm{V}_{\mathrm{DS}}=500 \mathrm{~V} ; \mathrm{V}_{\mathrm{GS}}=0 \mathrm{~V}$ |  | 1 | 25 | $\mu \mathrm{A}$ |
|  |  | $\mathrm{V}_{\text {DS }}=400 \mathrm{~V} ; \mathrm{V}_{\text {GS }}=0 \mathrm{~V} ; \mathrm{T}_{\mathrm{j}}=125^{\circ} \mathrm{C}$ | - | 30 | 250 | $\mu \mathrm{A}$ |
| $\mathrm{I}_{\text {GSS }}$ | Gate-source leakage current | $\mathrm{V}_{\mathrm{GS}}= \pm 30 \mathrm{~V} ; \mathrm{V}_{\text {DS }}=0 \mathrm{~V}$ | - | 10 | 200 | nA |
| $\begin{aligned} & \mathrm{Q}_{\mathrm{g}(\mathrm{tot)}} \\ & \mathrm{Q}_{\mathrm{gs}} \\ & \mathrm{Q}_{\mathrm{gd}} \\ & \hline \end{aligned}$ | Total gate charge Gate-source charge Gate-drain (Miller) charge | $\mathrm{I}_{\mathrm{D}}=6 \mathrm{~A} ; \mathrm{V}_{\mathrm{DD}}=400 \mathrm{~V} ; \mathrm{V}_{\mathrm{GS}}=10 \mathrm{~V}$ | - | $\begin{gathered} \hline 53 \\ 4 \\ 28 \end{gathered}$ | $\begin{gathered} 64 \\ 6 \\ 34 \end{gathered}$ | nC |
| $\begin{aligned} & \mathrm{t}_{\mathrm{d}(\text { (on })} \\ & \mathrm{t}_{\mathrm{r}} \\ & \mathrm{t}_{\text {d(of) })} \\ & \mathrm{t}_{\mathrm{f}} \\ & \hline \end{aligned}$ | Turn-on delay time Turn-on rise time Turn-off delay time Turn-off fall time | $\begin{aligned} & \mathrm{V}_{\mathrm{DD}}=250 \mathrm{~V} ; \mathrm{R}_{\mathrm{D}}=39 \Omega ; \\ & \mathrm{R}_{\mathrm{G}}=12 \Omega \end{aligned}$ | - - - | 10 33 92 40 | - - - | $\begin{aligned} & \mathrm{ns} \\ & \mathrm{~ns} \\ & \text { ns } \\ & \mathrm{ns} \end{aligned}$ |
| $\begin{array}{\|l} \mathrm{L}_{\mathrm{d}} \\ \mathrm{~L}_{\mathrm{s}} \end{array}$ | Internal drain inductance Internal source inductance | Measured from drain lead to centre of die Measured from source lead to source bond pad | - | $\begin{aligned} & 4.5 \\ & 7.5 \end{aligned}$ | - | $\begin{aligned} & \mathrm{nH} \\ & \mathrm{nH} \end{aligned}$ |
| $\mathrm{C}_{\text {iss }}$ $\mathrm{C}_{\text {oss }}$ $\mathrm{C}_{\text {rss }}$ | Input capacitance Output capacitance Feedback capacitance | $\mathrm{V}_{\mathrm{GS}}=0 \mathrm{~V} ; \mathrm{V}_{\mathrm{DS}}=25 \mathrm{~V} ; \mathrm{f}=1 \mathrm{MHz}$ | - | 610 <br> 96 <br> 54 | - | pF pF pF |

## SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS

$\mathrm{T}_{\mathrm{j}}=25^{\circ} \mathrm{C}$ unless otherwise specified

| SYMBOL | PARAMETER | CONDITIONS | MIN. | TYP. | MAX. | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{I}_{\text {s }}$ | Continuous source current | $\mathrm{T}_{\text {hs }}=25^{\circ} \mathrm{C}$ |  |  | 5.9 | A |
| $\mathrm{I}_{\text {SM }}$ | Pulsed source current (body | $\mathrm{T}_{\text {hs }}=25^{\circ} \mathrm{C}$ | - | - | 24 | A |
| $\mathrm{V}_{\text {SD }}$ | Diode forward voltage | $\mathrm{I}_{\mathrm{S}}=6 \mathrm{~A} ; \mathrm{V}_{\mathrm{GS}}=0 \mathrm{~V}$ | - |  | 1.5 | V |
| $\mathrm{t}_{\text {r }}$ | Reverse recovery time | $\begin{aligned} & \mathrm{I}_{\mathrm{s}}=6 \mathrm{~A} ; \mathrm{V}_{\mathrm{GS}}=0 \mathrm{~V} ; \mathrm{d} / / \mathrm{dt}=100 \mathrm{~A} / \mu \mathrm{s} \\ & \mathrm{IS}_{\mathrm{S}}=6 \mathrm{~A} ; \mathrm{V}_{\mathrm{GS}}=0 \mathrm{~V} ; \mathrm{dl} / \mathrm{dt}=100 \mathrm{~A} / \mu \mathrm{s} ; \end{aligned}$ |  | $\begin{aligned} & 180 \\ & 220 \end{aligned}$ |  | $\begin{aligned} & \mathrm{ns} \\ & \mathrm{~ns} \end{aligned}$ |
| $Q_{\text {r }}$ | Reverse recovery charge | $\mathrm{I}_{\mathrm{S}}=6 \mathrm{~A} ; \mathrm{V}_{\mathrm{GS}}=0 \mathrm{~V} ; \mathrm{d} / / \mathrm{dt}=100 \mathrm{~A} / \mu \mathrm{s}$ $\mathrm{I}_{\mathrm{S}}=6 \mathrm{~A} ; \mathrm{V}_{\mathrm{GS}}=0 \mathrm{~V} ; \mathrm{dl} / \mathrm{dt}=100 \mathrm{~A} / \mu \mathrm{s} ;$ | - | $\begin{gathered} 0.65 \\ 2.6 \end{gathered}$ | - | ${ }_{\mu}^{\mu \mathrm{C}} \mathrm{C}$ |
| $\mathrm{I}_{\text {rm }}$ | Peak reverse recovery current | $\begin{aligned} & \mathrm{I}_{\mathrm{s}}=6 \mathrm{~A} ; \mathrm{V}_{\mathrm{GS}}=0 \mathrm{~V} ; \mathrm{d} / \mathrm{dt}=100 \mathrm{~A} / \mu \mathrm{s} ; \\ & 125^{\circ} \mathrm{C} \end{aligned}$ | - | 15 | - | A |

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Fig.1. Normalised power dissipation. $P D \%=100 \cdot P_{D} / P_{D 25^{\circ} \mathrm{C}}=f\left(T_{h s}\right)$


Fig.2. Normalised continuous drain current. $I D \%=100 \cdot I_{D} / I_{D 25^{\circ} \mathrm{C}}=f\left(T_{h S}\right)$; conditions: $V_{G S} \geq 10 \mathrm{~V}$


Fig.3. Safe operating area. $T_{h s}=25^{\circ} \mathrm{C}$
$I_{D} \& I_{D M}=f\left(V_{D S}\right) ; I_{D M}$ single pulse; parameter $t_{p}$


Fig.4. Transient thermal impedance.
Fig.4. Transient thermal impedance. $Z_{t h j-h s}=f(t) ;$ parameter $D=t_{p} / T$


Fig.5. Typical output characteristics. $I_{D}=f\left(V_{D S}\right)$; parameter $V_{G S}$ $\qquad$


Fig.6. Typical on-state resistance. $R_{D S(O N)}=f\left(I_{D}\right)$; parameter $V_{G S}$

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Fig.7. Typical transfer characteristics. $I_{D}=f\left(V_{G S}\right) ;$ parameter $T_{j}$


Fig.8. Typical transconductance. $g_{f s}=f\left(I_{D}\right)$; parameter $T_{j}$


Fig.9. Normalised drain-source on-state resistance. $a=R_{D S(O N)} / R_{D S(O N) 25^{\circ} \mathrm{C}}=f\left(T_{j}\right) ; I_{D}=3 \mathrm{~A} ; V_{G S}=10 \mathrm{~V}$


Fig.10. Gate threshold voltage.
$V_{G S(T O)}=f\left(T_{j}\right) ;$ conditions: $I_{D}=0.25 m A ; V_{D S}=V_{G S}$


Fig.11. Sub-threshold drain current. $I_{D}=f\left(V_{G S}\right)$; conditions: $T_{j}=25^{\circ} \mathrm{C}$; $V_{D S}=V_{G S}$


Fig.12. Typical capacitances, $C_{\text {iss }}, C_{\text {oss }}, C_{\text {rsss }}$. $C=f\left(V_{D S}\right) ;$ conditions: $V_{G S}=0 \mathrm{~V} ; f=1 \mathrm{MHz}$


Fig.13. Typical turn-on gate-charge characteristics. $V_{G S}=f\left(Q_{G}\right) ;$ parameter $V_{D S}$


Fig.14. Typical switching times; $t_{d(o n)}, t_{r}, t_{d(0 f f)}, t_{f}=f\left(R_{G}\right)$


Fig.16. Source-Drain diode characteristic. $I_{F}=f\left(V_{S D S}\right)$; parameter $T_{j}$


Fig.17. Maximum permissible non-repetitive avalanche current $\left(I_{A S}\right)$ versus avalanche time $\left(t_{D}\right)$; unclamped inductive load


Fig.15. Normalised drain-source breakdown voltage; $V_{(B R) D S S} / V_{(B R) D S S ~ 25{ }^{\circ}}{ }^{\circ}=f\left(T_{j}\right)$


Fig.18. Maximum permissible repetitive avalanche current $\left(I_{A R}\right)$ versus avalanche time ( $t_{p}$ )

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## MECHANICAL DATA



Fig.19. SOT186A; The seating plane is electrically isolated from all terminals.

## Notes

1. Observe the general handling precautions for electrostatic-discharge sensitive devices (ESDs) to prevent damage to MOS gate oxide.
2. Refer to mounting instructions for F-pack envelopes.
3. Epoxy meets UL94 V0 at $1 / 8^{\prime \prime}$.

## DEFINITIONS

| Data sheet status |  |
| :--- | :--- |
| Objective specification | This data sheet contains target or goal specifications for product development. |
| Preliminary specification | This data sheet contains preliminary data; supplementary data may be published later. |
| Product specification | This data sheet contains final product specifications. |
| Limiting values | Limiting values are given in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one <br> or more of the limiting values may cause permanent damage to the device. These are stress ratings only and <br> operation of the device at these or at any other conditions above those given in the Characteristics sections of <br> this specification is not implied. Exposure to limiting values for extended periods may affect device reliability. |
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